

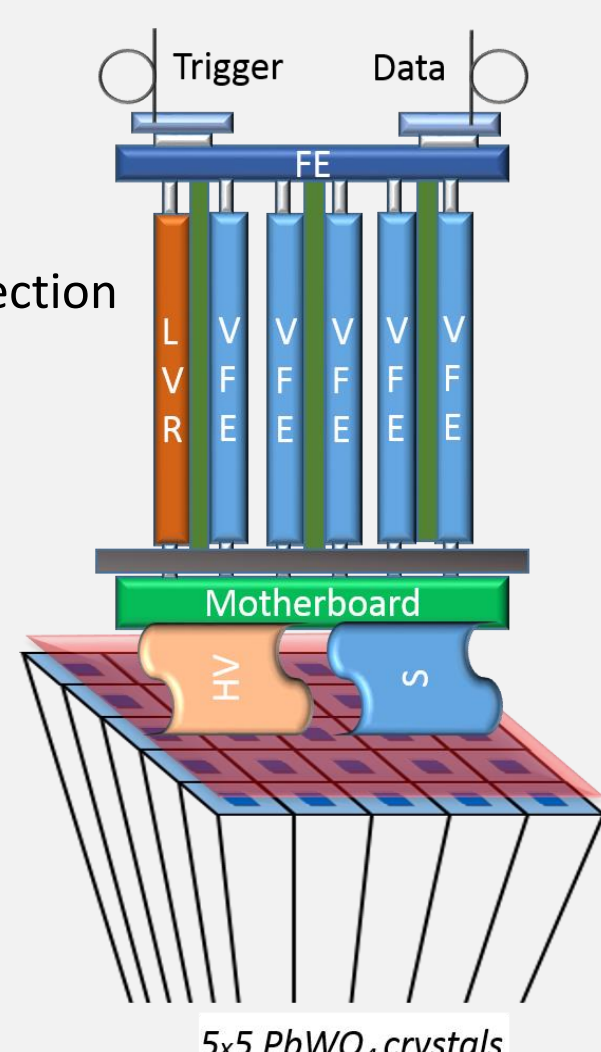
# The CMS phase 2 ECAL front end electronics upgrade

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The CMS ECAL barrel electronics will be upgraded for the HL-LHC to comply with increased latency and bandwidth requirements of the Level 1 trigger, to preserve detector performance despite the increased instantaneous luminosity, and to provide a precision timing measurement in addition to energy. The chosen solution includes a custom dual gain trans-impedance amplifier implemented in a 130 nm CMOS process and a dual ADC ASIC implementing gain selection and data compression implemented in a 65 nm CMOS process.

## ECAL Barrel electronics

- 1 Module called "Trigger Tower":
  - Readout of 5x5 crystals matrix.
  - Each crystal has 2 APDs glued, connected in parallel
- Motherboard:
  - Passive board used to provide HV for APDs and VFE inputs connection
- Very Front End (VFE):
  - 5 cards / module
  - Each VFE has 5 identical readout channels with pre-amplifier (MGPA), filter and 12-bit ADC
- Front-end card (FE):
  - This card generates trigger data summing of 5x5 crystal signals and has latency buffer (< 6µs) to store data while waiting for L1 accept.
  - The readout between data & trigger is separated.
  - 40 MHz readout of the tower
  - 100 kHz readout of single crystals for triggered events
- Low Voltage Regulator card (LVR):
  - 10 linear radiation tolerant regulators

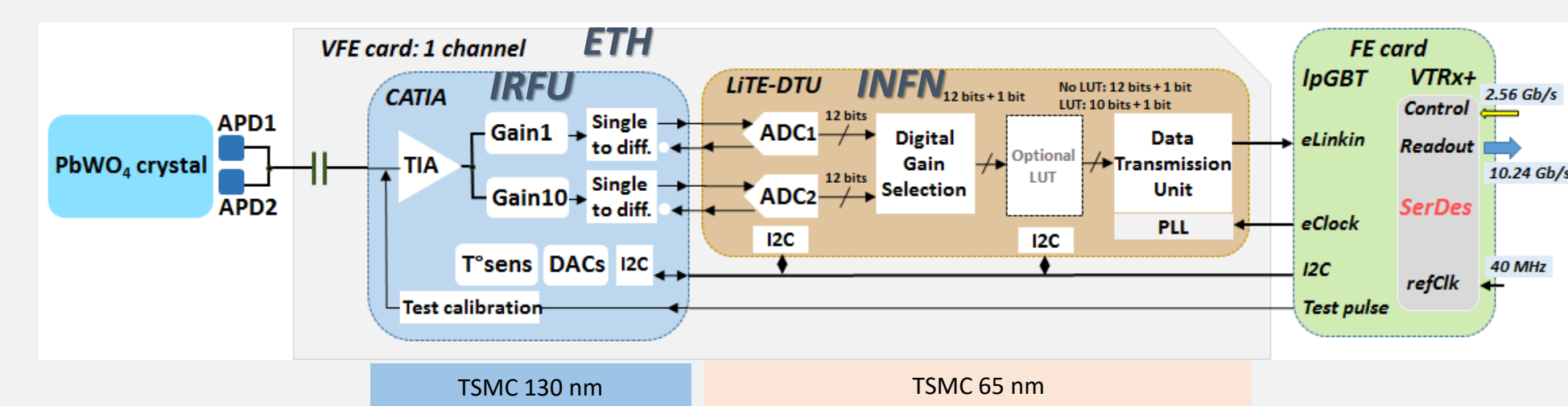


## CMS Barrel ECAL upgrade at HL-LHC

Extraction and refurbishment of the 36 EB Super modules during LS3

- Replace FE and VFE cards:
  - To be compatible with increased Phase II trigger requirements
  - To cope with challenging HL-LHC conditions (noise, PU, anomalous APD signals) keeping the dynamic range
  - To increase the time measurement resolution for high energy photons
- Reduce temperature from 18° C to 8° C:
  - To mitigate the increase of APD dark current with the radiation
- Off-detector electronics upgraded to:
  - Higher transfer rates
  - Generation of trigger primitives
- SLVR card:
  - DCDC radiation + magnetic field tolerant
- PbWO<sub>4</sub> crystals, APDs, Motherboards & overall mechanical structure will remain

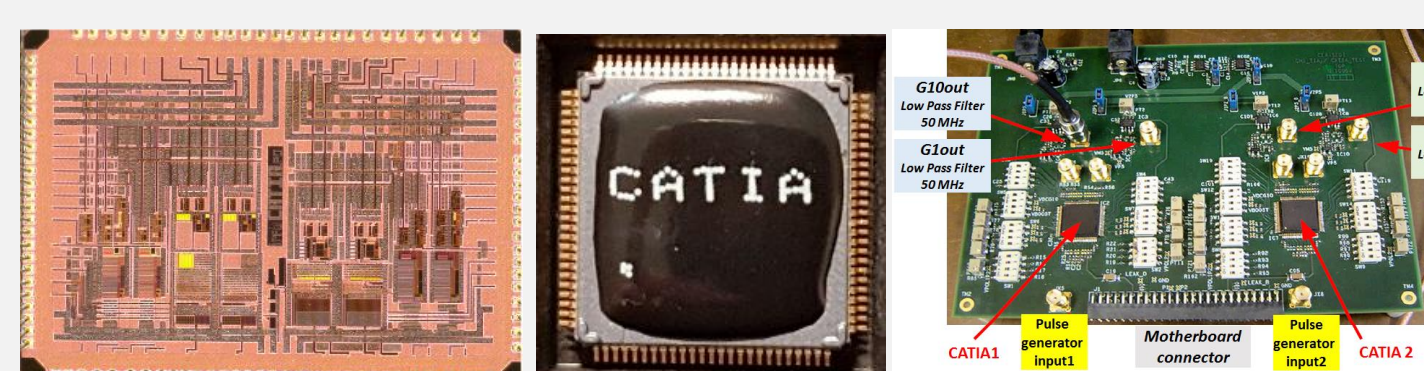
## CMS Barrel ECAL VFE upgrade: TIA + Fast ADC



- CATIA (Calorimeter Trans Impedance Amplifier) ASIC:
  - TIA & 2 Gain stages (G1, G10); Test calibration; T<sup>o</sup> sensor; I2C
- LITE-DTU (Lisbon-Torino ECAL Data Transmission Unit) ASIC:
  - 12-bit ADC, 160 MHz sampling, dual channel with gain selection logic: IP from external supplier
  - Data Transmission Unit (DTU) implements data compression before FE
- FE:
  - IpGBT (4x10.24 Gb/s data links, 1x2.56 Gb/s control link)
  - eLink serial interface to ADC, clock and I2C interface
- Low Voltage Regulator (LVR):
  - needed voltages (1.2V & 2.5V) supplied by point-of-load FEAST DC/DC converters

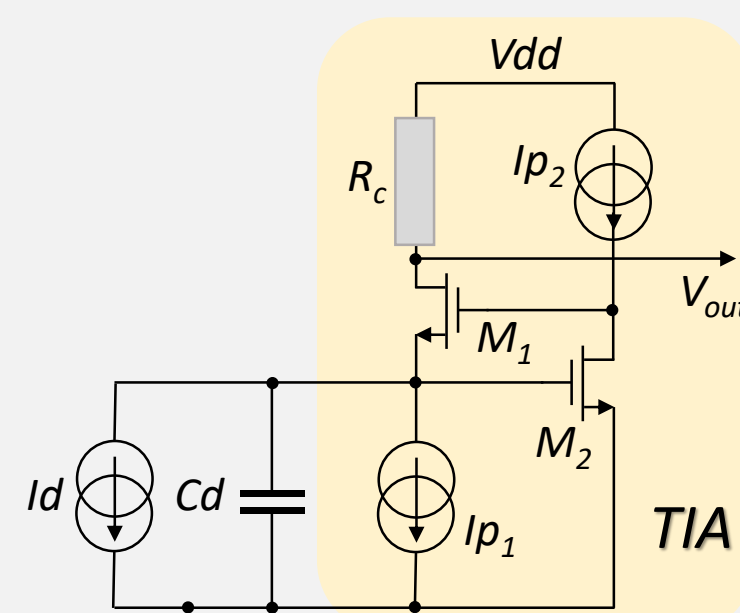
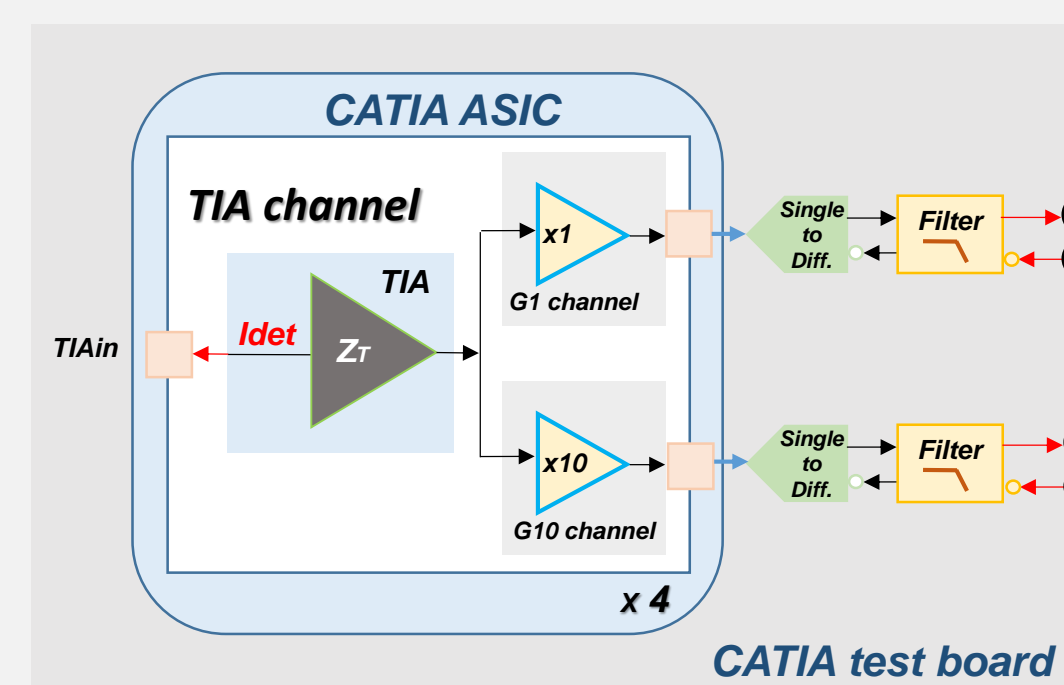
## CATIA V0 : main features

- First prototype
  - Proof of concept : TIA instead of CSA (legacy architecture)
  - Transistors flavor selection (1.2V or 2.5V)
  - Full characterization with detectors



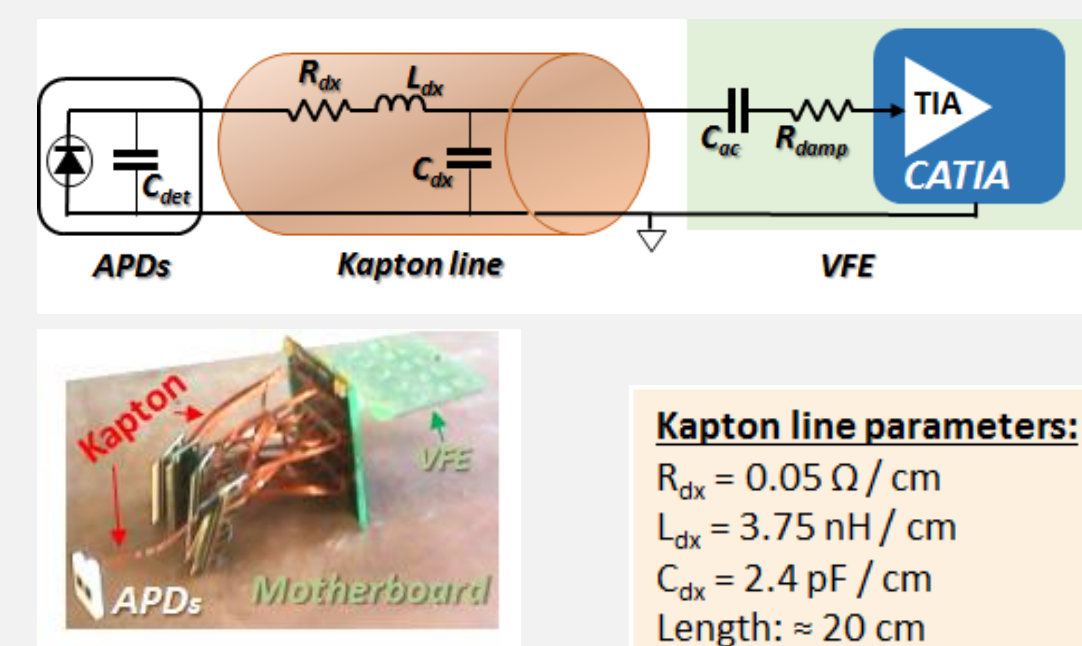
CATIA V0

- Process: TSMC 130 nm
- 2352µm x 3323µm
- LQFP 100L 14x14
- Test: 2017



TIA architecture

- Regulated Common-Gate (RCG):
  - low  $Z_{in}$  (< 1 Ω) compatible with 50 MHz of bandwidth for  $C_d = 200$  pF

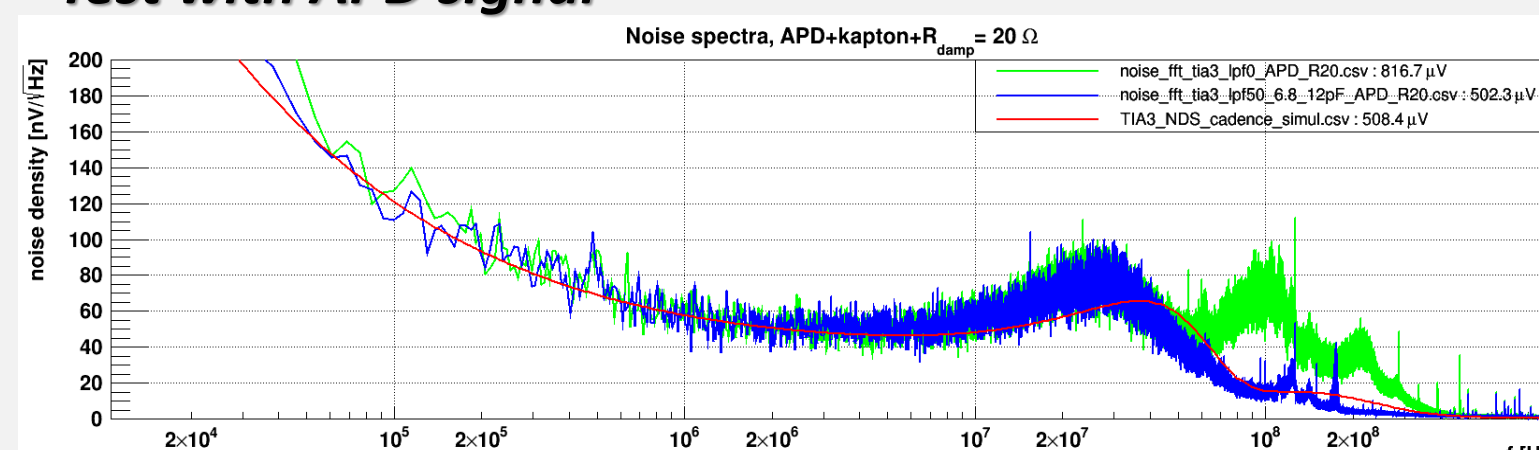


APD to TIA input: strip lines

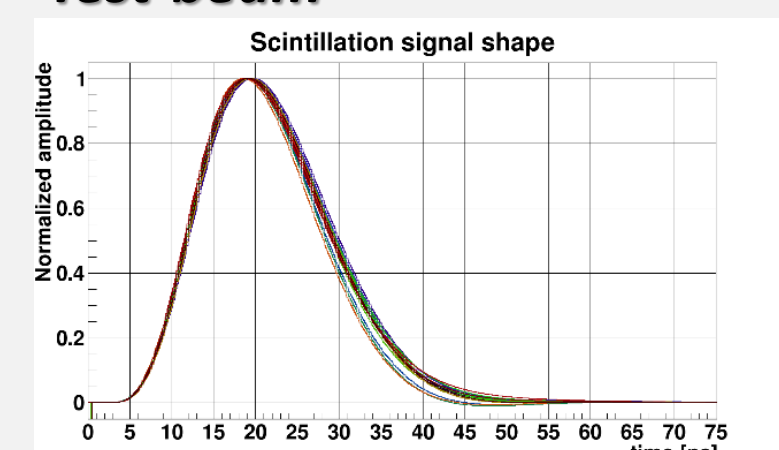
High value of inductance (75 to 100 nH):  
 Need damping resistor to ensure stability  
 => Impact on the BW, timing & charge resolution

## CATIA V0 : test results summary<sup>1</sup>

### Test with APD signal



### Test-beam



Noise density spectra of CATIA connected to APDs as in ECAL. In green, without bandwidth limitations, in blue with a low pass filter at 50 MHz and in red the simulation results

H4 Test-beam April 2018  
 Response of 15 crystals:  
 CATIA-V0 + 14-bit ADC 160 MS/s

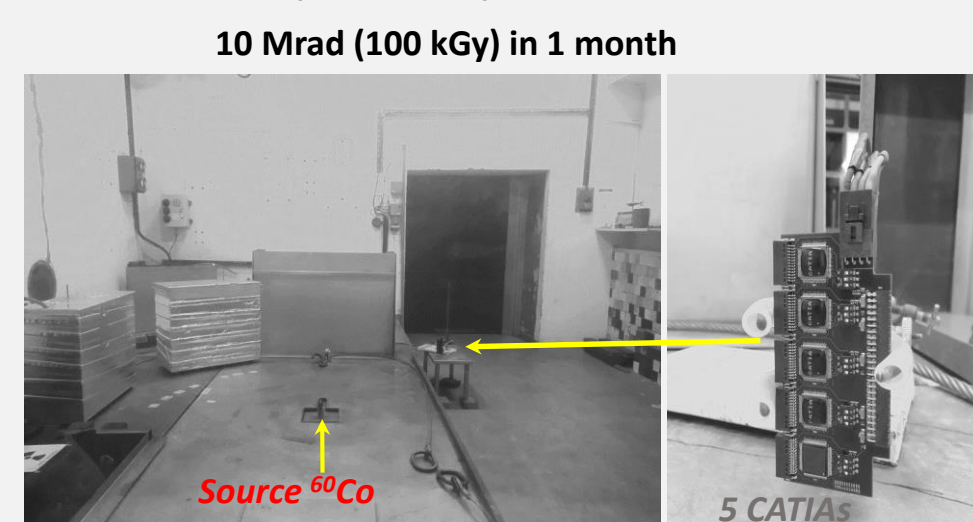
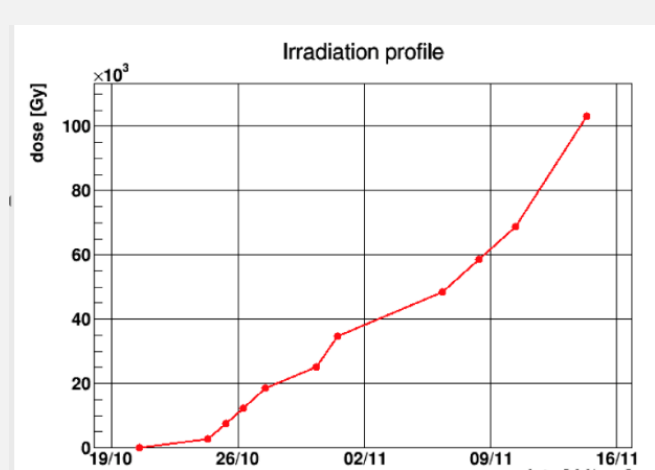
- The test results are very consistent with simulation results
- For the final version, it will be interesting to choose the thick oxide transistors (2.5 V):
- Advantages: better dynamic range, linearity and noise performances
- But thick oxide is expected to be less tolerant to radiation (expected 1 Mrad, required tolerance > 10 Mrad)

=> radiation test mandatory

<sup>1</sup>For more test results see poster TWEPP 2017

## Irradiation tests

- Irradiation at *Pagure* in 2017: CEA-Saclay facility

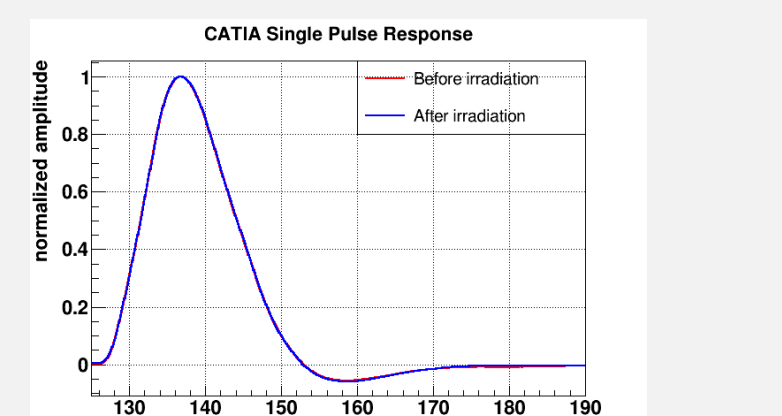


- Test 1.2V and 2.5V versions on 5 prototypes

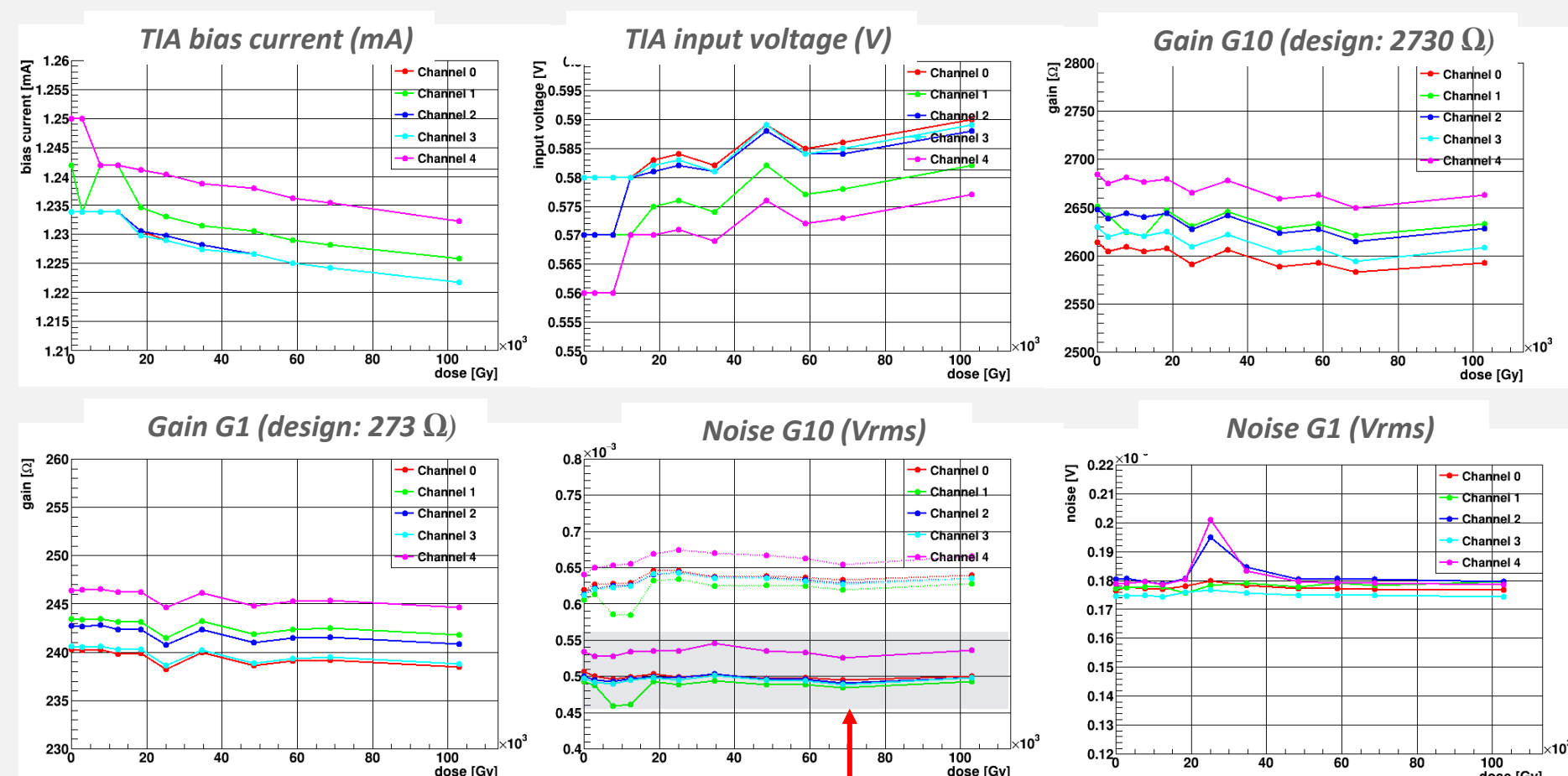
- Power supplies current
- TIA bias current (1), TIA input voltage (2)
- TIA output voltage for G1 and G10 (3)
- Noise, Gain-linearity, Bandwidth, rise time

- Transient response with detector:

- 10 Mrad
- TIA 2.5 V
- G1



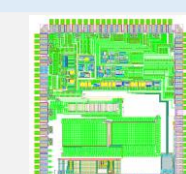
- 2.5V thick oxide TIA results:



- Conclusions

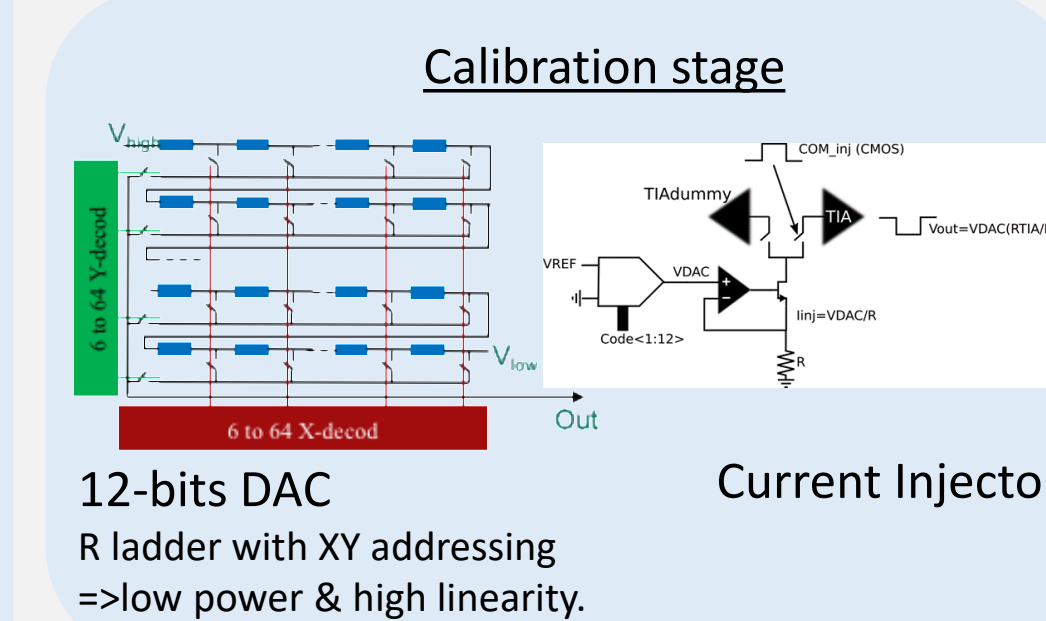
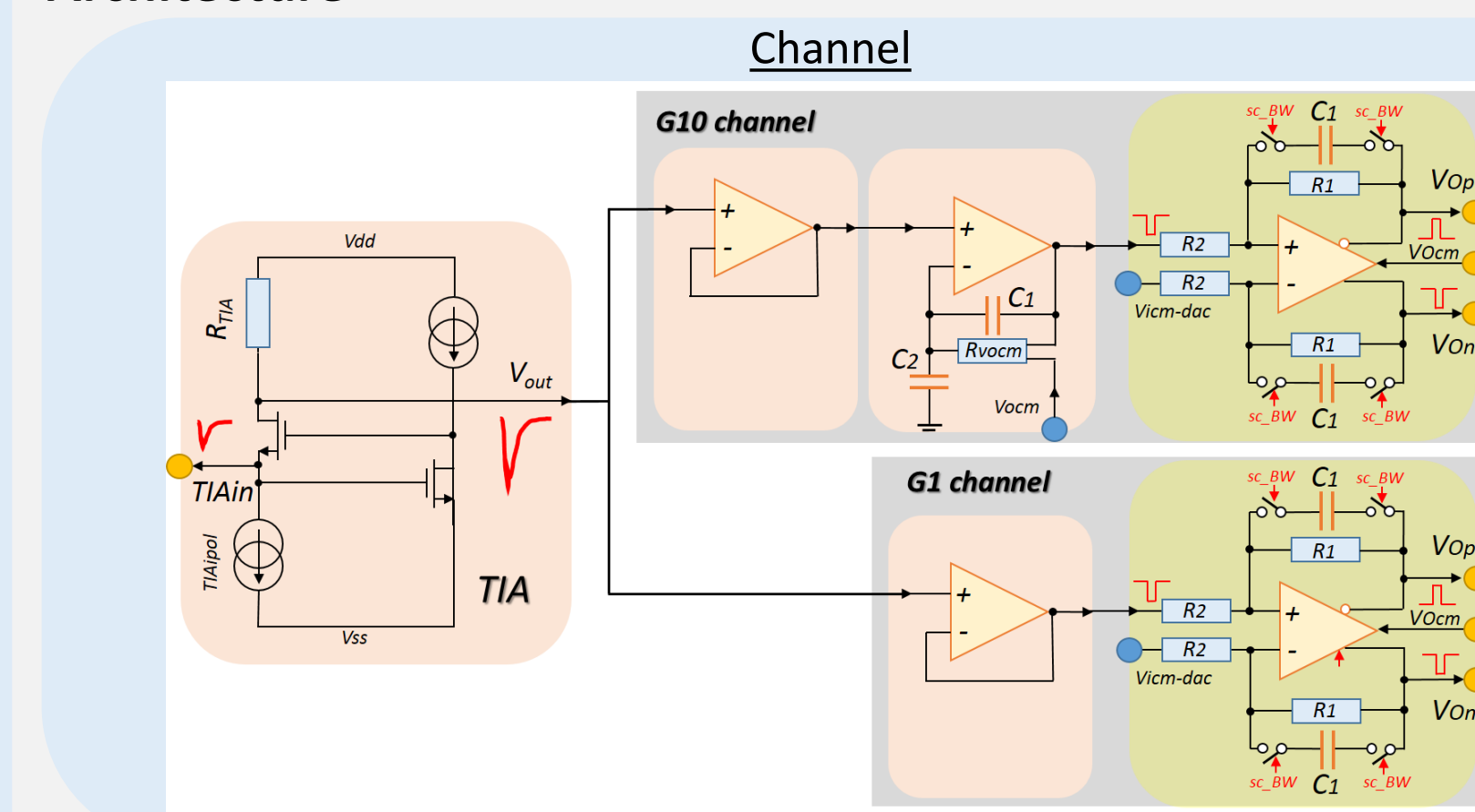
- Radiation hardness test shows that the 2.5V thick oxide CATIA version meets the radiation hardness requirements for CMS ECAL barrel and is selected as the baseline for the CATIA V1

## CATIA V1



- Based on current amplifier TIA used in CATIA-V0
- 2 differential voltage outputs covering 2 input dynamic charge ranges: 10 MeV-200 GeV & 10 MeV-2 TeV
- Must be interfaced with 12-bit ADC: +/- 0.6 V per input; Vicm = 0.6V
- ASIC integration by INFN.
- Integrated Filter to control the bandwidth of the analog signal processing
- Calibration system with 2/1000 of precision (12 bits current source)
- I2C with TMR for slow control (gain, bandwidth, calibration...)
- Temperature sensor (-40 to +80°C, 1.3mV/°C) based on CERN Bandgap
- Technology: 130 nm TSMC; 1.2 & 2.5 V

### Architecture



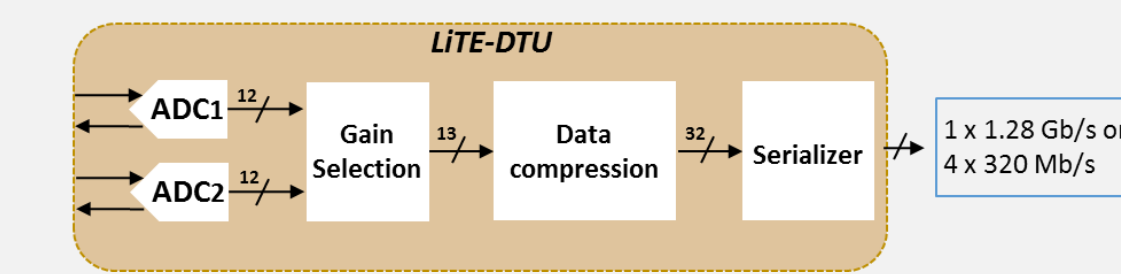
### Simulation results

luminosity	Ileak	E Resolution; η = 0	T Resolution @ 50 GeV; η = 0	Ileak	E Resolution; η = 1.45	T Resolution @ 50 GeV; η = 1.45
300 fb <sup>-1</sup>	5 µA	105 MeV	15 ps	10 µA	135 MeV	21 ps
4500 fb <sup>-1</sup>	80 µA	380 MeV	57 ps	140 µA	890 MeV	134 ps

Submitted in July 2018 => test results before 2019.

## LITE-DTU Architecture

- ADC
  - IP provided by S3 Group guided by LIP
  - ASIC integration by INFN.
- DTU
  - Data compression and Transmission at 1 x 1.28 Gb/s or 4x320 Mb/s



### ADC requirements

Specification	min	typ	max	unit
Sampling rate	160			MS/s
Resolution	12			bit
Supply voltage	1.08	1.2	1.32	V
Differential input range			± 0.6	V
DNL			± 0.9	LSB
INL			± 1.5	LSB
Operational temperature	-20	25	85	°C
Power consumption	20			mW
Calibration time	15			T <sub>CK</sub>
Calibration time	38200			T <sub>CK</sub>
Technology	CMOS 65 nm (9+1 metal stack)			
TID tolerance	20			kGy
SEU tolerance	15			MeV cm <sup>2</sup> /mg

### ADC IP block

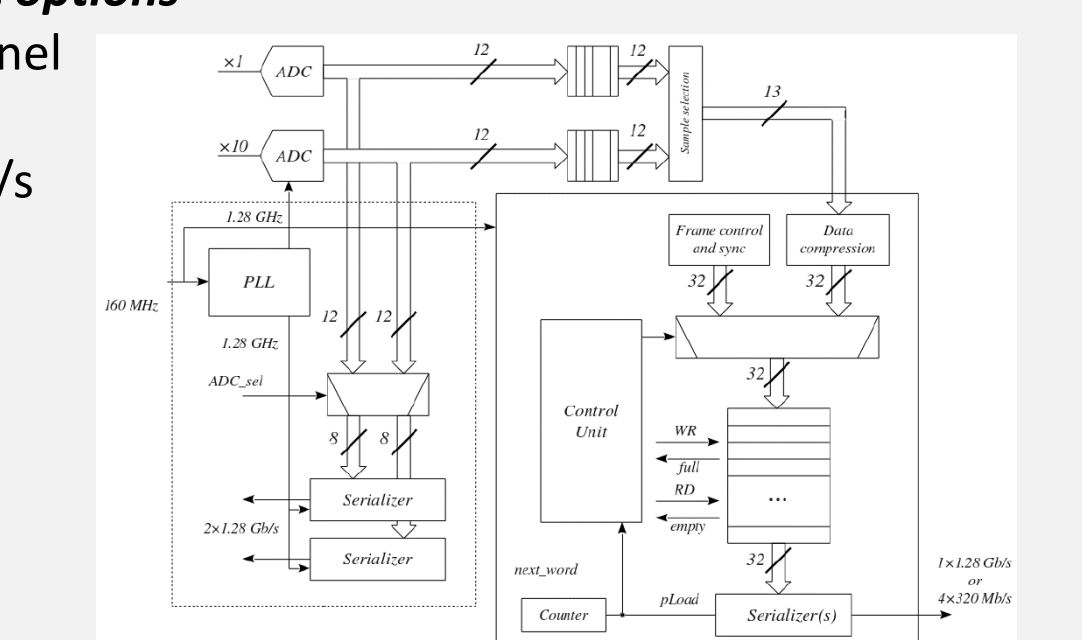
- This ADC is based on original ADC designed in 40 nm technology
- Time Interleaved dual core architecture.
- Each core 12bits, 80 MS/s SAR ADC
- TMR on control logic and RD53-based design guidelines (for TID tolerance)
- Delivery of full gdsII: September 2018

### DTU architecture

- Data compression
  - Word size 32 bits in order to minimize the BW for baseline samples (< 7 bits)
  - Total bandwidth without compression: 160 MS/s x 13 bits = 2.08 Gb/s
  - Probability to have an event with more than 6 bits < 2.37 10<sup>-4</sup>
  - Baseline rate: 160 MS/s x (1-2.37 10<sup>-4</sup>) x 32/5 = 1.024 Gb/s
  - Signal rate: 160 MS/s x 2.37 10<sup>-4</sup> x 32/2 = 0.61 Mb/s
  - Baseline rate close to signal: 160 MS/s x 2.37 10<sup>-4</sup> x 32 = 1.22 Mb/s
  - Protocol overhead (estimated): 50 Mb/s

### Bandwidth comparison & Readout options

- Total bandwidth required per channel 1.08 Gb/s
- Total bandwidth available: 1.28 Gb/s (distributed over 1, 2 or 4 e-links)



Submission: November 2018.

## Conclusion

- The ECAL Barrel VFE must be redesigned for the upgrade phase II
- The new VFE architecture will be faster by using TIA coupled with ADC 160 MS/s
- Submission & test including radiation hardness (TID) of the first prototype CATIA-V0 permit to validate the choice of this solution for ECAL at HL-LHC. The new version CATIA-V1 is more complete and compatible with the 12-bit ADC chosen also for ECAL VFE. The ASIC has been submitted the 4<sup>th</sup> of July 2018 and will be tested before end 2018. Some news hopefully at TWEPP 2019.
- The first prototype of 12-bit ADC will be provided by S3 in September 2018. The first complete LITE-DTU will be submitted in November 2018.